

PCTEST

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HEARING AID COMPATIBILITY

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 3/16/2020 - 3/19/2020 Test Site/Location: PCTEST, Columbia, MD, USA Test Report Serial No.: 1M2003120043-21-R1.A3L Date of Issue:

4/13/2020

FCC ID: A3LSMG986U

APPLICANT: SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: Audio Band Magnetic Testing (T-Coil)

Application Type: Class II Permissive Change

FCC Rule Part(s): CFR §20.19(b)
HAC Standard: ANSI C63.19-2011

CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017

285076 D01 HAC Guidance v05

285076 D02 T-Coil testing for CMRS IP v03

DUT Type: Portable Handset SM-G986U SM-G986U1

Test Device Serial No.: Pre-Production Sample [S/N: 0923M, 0468M]

Class II Permissive Change(s): See FCC Change Document

Original Grant Date: 1/24/2020

C63.19-2011 HAC Category: T4 (SIGNAL TO NOISE CATEGORY, NR Only)

This report and category pertain only to NR modes supported by this wireless portable device. The overall category rating of the device is determined by the lowest rating obtained over all air interfaces supported by the device. This wireless portable device has been shown to be hearing-aid compatible for NR modes, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.









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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

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2. **DUT DESCRIPTION**



FCC ID: A3LSMG986U

Applicant: Samsung Electronics Co., Ltd.

129, Samsung-ro, Maetan dong,

Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Model: SM-G986U Additional Model(s): SM-G986U1 Serial Number: 0923M, 0468M

HW Version: Rev.1.0

SW Version: G986USQU1ATB3 Antenna: Internal Antenna **DUT Type:** Portable Handset

I. **Device Serial Numbers**

Several samples with identical hardware were used to support HAC testing. The manufacturer has confirmed that the device(s) tested have the same physical, mechanical, and thermal characteristics are within operational tolerances expected for production units. The serial numbers used for each test are indicated alongside the results in Section 6.

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Table 2-1 SM-G986U &SM-G986U1 HAC Air Interfaces

		Siv	1-03000	ASIVI-GUODO I HAC AII	IIILEIIACES	
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	Audio Codec Evaluated
	835	vo	No ¹	Yes: WIFI or BT	CMRS Voice	EVRC
CDMA	1900	VO	NO	res. Will of Bi	CIVING VOICE	LVIC
	EvDO	VD	No ¹	Yes: WIFI or BT	Google Duo	OPUS
GSM	850 1900	vo	No ¹	Yes: WIFI or BT	CMRS Voice	EFR
GSIVI	GPRS/EDGE	VD	No ¹	Yes: WIFI or BT	Google Duo	OPUS
	850	,,,	140	163. WIIT 61 21	Coogle 540	0.00
	1700	VD	No ¹	Yes: WIFI or BT	CMRS Voice	NB AMR
UMTS	1900					
	HSPA	VD	No ¹	Yes: WIFI or BT	Google Duo	OPUS
	680 (B71)		No ¹			
	700 (B12)					
	780 (B13)					Volte: NB AMR, WB AMR, EVS
	790 (B14)					
	850 (B5)				VoLTE, Google Duo	
LTE (FDD)	850 (B26)	VD		Yes: WIFI or BT		
LIE (FDD)	1700 (B4)	VD.	No ¹	res. WIFI OF BT	VOLTE, GOOGIE DUO	Google Duo: OPUS
	1700 (B66)					
	1900 (B2)					
	1900 (B25)					
	2300 (B30)					
	2500 (B7)					
	2600 (B38)			N-12	VoLTE: NB AMR, WB AMR, EVS	
LTE (TDD)	2600 (B41)	VD	No ¹	Yes: WIFI or BT	VoLTE, Google Duo	Google Duo: OPUS
	3600 (B48)					
	680 (n71)		Yes ¹³			
NR (FDD)	850 (n5)	VD		Yes: WIFI or BT	Google Duo ²	OPUS
` '	1700 (n66)		Yes ¹		2008:0 200	
	1900 (n2)					
	2600 (n41)	<u> </u>	Yes ¹			
NR (TDD)	28000 (n261)	VD	No ⁴	Yes: WIFI or BT	Google Duo ²	OPUS
	39000 (n260)					
	2450					
	5200 (U-NII 1)		1	V 60444 6644 HATE LTE AIR	V 10051 6 1 5	VoWIFI: NB AMR, WB AMR, EVS
WIFI	5300 (U-NII 2A)	VD	No ¹	Yes: CDMA, GSM, UMTS, LTE, or NR	VoWIFI, Google Duo	Google Duo: OPUS
	5500 (U-NII 2C)	1				
BT	5800 (U-NII 3) 2450	DT	No	Yes: CDMA, GSM, UMTS, LTE, or NR	N/A	N/A
Type Transport		UI	Notes:	Tes. COIVIA, GSIVI, GIVITS, LTE, OF INK	IN/A	IN/M
102 – Voice Only 1. This report only pertains to NR modes. For full data, please refer to the Original Certification Test Report (Repo				t Report (Report S/N:		
_	DT = Digital Data - Not intended for Voice Services 1M1910220166-21-R2.A3L).					
VD = CMRS and	VD = CMRS and/or IP Voice over Data Transport 2. Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 3. NR n71, while outside the scope of ANSI C63.19 and FCC HAC regulations, was additionally tested according to the existing				according to the existing UAC	
	5. IN IT73, while outside the stupe of ANSI COST and FCC FAC regulations, was admitted in the existing FAC procedures with currently available test equipment.				according to the existing HAC	

procedures with currently available test equipment.

4. n260 and n261 are currently outside the scope of ANSI C63.19 and FCC HAC regulations therefore they were not evaluated.

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3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be \geq -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.

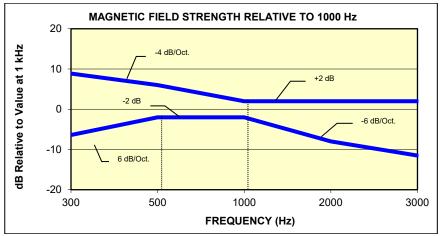


Figure 3-1
Magnetic field frequency response for Wireless Devices with an axial field ≤-15 dB(A/m) at 1 kHz

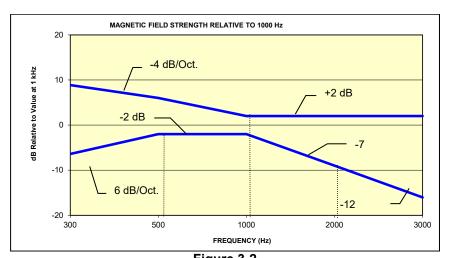


Figure 3-2
Magnetic Field frequency response for wireless devices with an axial field that exceeds
-15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters		
Category	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]		
T1	0 to 10 dB		
T2	10 to 20 dB		
Т3	20 to 30 dB		
T4	> 30 dB		
Table 3-1 Magnetic Coupling Parameters			

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

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4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

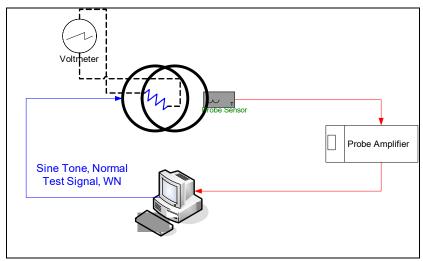


Figure 4-1 Validation Setup with Helmholtz Coil

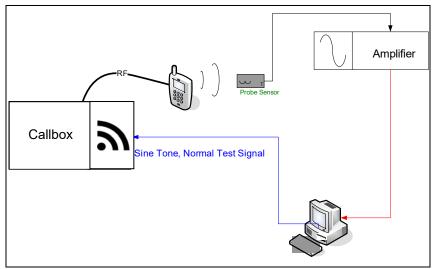


Figure 4-2 T-Coil Test Setup

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II. **Scanning Mechanism**

Manufacturer: TEM

Accuracy: ± 0.83 cm/meter

Minimum Step Size: 0.1 mm Maximum speed 6.1 cm/sec Line Voltage: 115 VAC Line Frequency: 60 Hz

Material Composite: Delrin (Acetal) Data Control: Parallel Port

45 x 31.75 x 47 cm Dynamic Range (X-Y-Z):

36" x 25" x 38" Dimensions: 36" x 49" x 55" Operating Area:

Reflections: < -20 dB (in anechoic chamber)

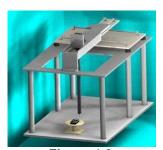


Figure 4-3 RF Near-Field Scanner

III. **3GPP2 Normal Test Signal (Speech)**

Manufacturer: 3GPP2 (TIA 1042 §3.3.1)

Modified-IRS weighted, multi-talker speech signal, 4 Male and 4

Stimulus Type: Female speakers (alternating)

Single Sample Duration: 51.62 seconds

Activity Level: 77.4%

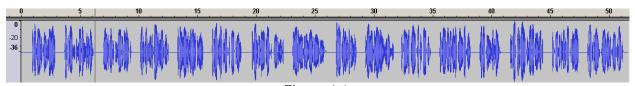
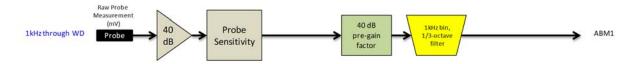


Figure 4-4 **Temporal Characteristic of Normal Test Signal**

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ABM2 Measurement Block Diagram:



Figure 4-5 Magnetic Measurement Processing Steps

IV. **Test Procedure**

- 1. Ambient Noise Check per C63.19 §7.3.1
 - Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - "A-weighting" and Half-Band Integration was applied to the measurements.
 - Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

- 2. Measurement System Validation (See Figure 4-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - ABM1 Validation

The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^3}}$$

Where H_c = magnetic field strength in amperes per meter N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.13m; R=10.193Ω and using V=29mV:

$$H_c = \frac{20 \cdot (\frac{0.029}{10.193})}{0.13 \cdot \sqrt{1.25^3}} = 0.316A/m \approx -10dB(A/m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 29mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within ± 0.5 dB of the -10dB(A/m) value (see Page 21).

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c. Frequency Response Validation
The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1kHz, between 300 – 3000 Hz using the Normal signal as shown below:



Figure 4-6 Frequency Response Validation

d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 4-1
ABM2 Frequency Response Validation

	HBI, A -	HBI, A -	
f (Hz)	Measured	Theoretical	dB Var.
	(dB re 1kHz)	(dB re 1kHz)	
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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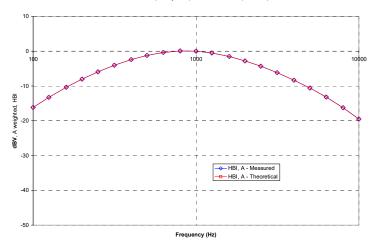
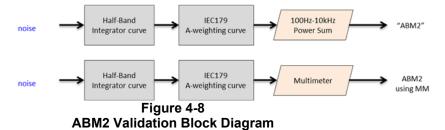


Figure 4-7
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 4-2
ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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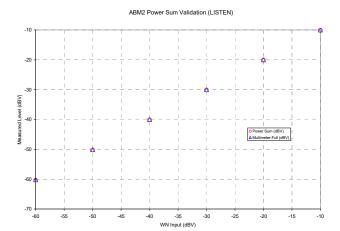
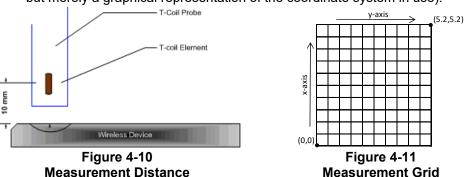


Figure 4-9 **ABM2 Power Sum Validation**

- 3. Measurement Test Setup
 - a. Fine scan above the WD (TEM)
 - i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):



- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-13 after a T-coil orientation was fully measured with the SoundCheck system.
- b. Speech Signal Setup to Base Station Simulator
 - i. C63.19 Table 7-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
IDENTM	TDMA (22 and 11 Hz)	-18

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- ii. See Section 5 for more information regarding audio level settings for Over-The-Top (OTT) Voice Over IP (VoIP) Testing.
- c. Real-Time Analyzer (RTA)
 - The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection
 - The device was chosen to be tested in the worst-case ABM2 condition (NR configuration information can be found in Section 5).
- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
 - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
 - iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
 - c. Signal Quality Index
 - i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
 - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
 - This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

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V. Test Setup

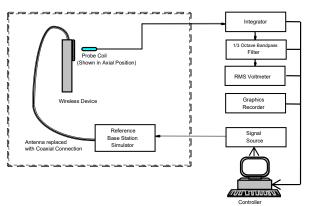


Figure 4-12
Audio Magnetic Field Test Setup

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection due to inaccessible RF ports.

VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS or pre-installed OTT VoIP applications were tested for T-coil unless otherwise noted. See Table 2-1 for more details regarding which modes were tested.

VIII. Wireless Device Channels and Frequencies

1. 5G (NR) Modes

The middle channel and supported bandwidths from the worst-case FDD band according to Table 5-2 was evaluated with OTT VoIP for each probe orientation. TDD was evaluated with n41. For both FDD and TDD, the band and bandwidth combination from each probe orientation resulting in the worst-case SNNR was additionally tested using low and high channels for that band and bandwidth combination. See Tables 6-2 to 6-3 for NR bandwidths and channels.

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IX. **Test Flow**

The flow diagram below was followed (From C63.19):

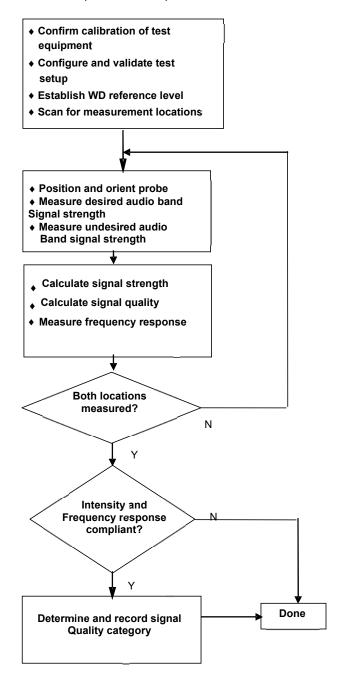


Figure 4-13 C63.19 T-Coil Signal Test Process

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5. OTT VOIP TEST SYSTEM AND DUT CONFIGURATION

I. Test System Setup for OTT VoIP T-Coil Testing

1. OTT VoIP Application

Google Duo is a pre-installed application on the DUT which allows for VoIP calls in a held-to-ear scenario. Duo uses the OPUS audio codec and supports a bitrate range of 6kb/s to 75kb/s. All air interfaces capable of a data connection were evaluated with Google Duo.

2. Audio Level Settings

According to KDB 285076 D02, the average speech level of -20dBm0 shall be used for protocols not specifically listed in Table 7.1 of ANSI C63.19-2011 or the ANSI C63.19-2011 VoLTE interpretation². The auxiliary VoIP unit allowed for monitoring the signal input level to ensure that the settings for speech input and full scale levels resulted in the -20dBm0 speech input level to the DUT for the OTT VoIP call.

Note: The green highlighted text is approved by FCC under the TCB PAG Re-Use Policy 388624 D01 IV. D. for T-Coil Testing for WI-FI calling and Google Duo.

² FCC Office of Engineering and Technology KDB, "285076 D02 T-Coil Testing for CMRS IP v03," September 13, 2017

1 00 office of Engineering and Technology NDB, 200070 Bb2 1-0011 Testing for Office in 100, Oction Bc1 10, 2017							
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II. **DUT Configuration for OTT VolP T-Coil Testing**

1. Radio Configuration for OTT VoIP (NR)

An investigation was performed to determine the RB configuration to be used for testing. Due to equipment limitations, ABM1 measurements were not possible. Therefore, additional ABM1 measurements with LTE OTT VoIP were used from the Original Certification Test Report and combined with NR ABM2 measurements to obtain SNNR values. DFT-s-OFDM π/2-BPSK, 1RB, 50%RB offset was determined to be the worst-case configuration for the handset and will be used for full testing in Section 6.

> Table 5-1 NR OTT VolP SNNR by Radio Configuration (DFT-s-OFDM)

Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	1	1	10.47	-47.10	57.57
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	1	53	10.47	-45.78	56.25
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	1	104	10.47	-47.04	57.51
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	50	0	10.47	-49.06	59.53
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	50	28	10.47	-47.79	58.26
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	50	56	10.47	-48.29	58.76
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	100	0	10.47	-48.37	58.84

An investigation was performed to determine the worst-case NR FDD band to be used for OTT VoIP testing. NR FDD n2 was used for the testing as the worst-case configuration for the handset. See below table for SNNR comparison between different NR bands:

> Table 5-2 OTT VoIP (NR) SNNR by Band

Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Waveform	Modulation	RB Size	RB Offset	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
n71	680.5	136100	20	DFT-s-OFDM	π/2-BPSK	1	53	10.47	-47.08	57.55
n5	836.5	167300	20	DFT-s-OFDM	π/2-BPSK	1	53	10.47	-46.97	57.44
n66	1745.0	349000	20	DFT-s-OFDM	π/2-BPSK	1	53	10.47	-47.01	57.48
n2	1880.0	376000	20	DFT-s-OFDM	π/2-BPSK	1	53	10.47	-45.64	56.11

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T-COIL TEST SUMMARY

Table 6-1 **Consolidated Tabled Results**

	Freq. Response Magnetic FCC SNNR Intensity Verdict Verdict		Margin from FCC Limit	C63.19-2011							
C62.10	9 Section	8.3.2		8.3	8.3.1		3.4	(dB)	Rating		
C03. 1s	9 Section	Axial	Radial	Axial	Radial	Axial	Radial				
NR FDD (OTT VoIP) NR TDD (OTT VoIP) n2		NA	NA	PASS	PASS	PASS	PASS	-29.70	T4		
		NA	NA	PASS	PASS	PASS	PASS	-13.23	T4		

Raw Handset Data

Table 6-2 Raw Data Results for NR FDD n2 (OTT VoIP)

Mode	Orientation	Bandwidth	Channel	Sample S/N	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	380000	0923M	10.47	-45.38		N/A	55.85	20.00	-35.85	T4	
		20MHz	376000	0923M	10.47	-44.88	-58.13		55.35	20.00	-35.35	T4	0.8, 2.4
	Axial	20MHz	372000	0923M	10.47	-45.72			56.19	20.00	-36.19	T4	
	Axiai	15MHz	376000	0923M	10.47	-45.23			55.70	20.00	-35.70	T4	
		10MHz	376000	0923M	10.47	-46.50			56.97	20.00	-36.97	T4	
NR n2		5MHz	376000	0923M	10.47	-46.22			56.69	20.00	-36.69	T4	
NK IIZ		20MHz	376000	0923M	3.47	-46.33			49.80	20.00	-29.80	T4	
		15MHz	376000	0923M	3.47	-46.41			49.88	20.00	-29.88	T4	
	Radial	10MHz	376000	0923M	3.47	-46.37	-58.89	N/A	49.84	20.00	-29.84	T4	0.8, 1.6
	radiai	5MHz	381500	0923M	3.47	-46.39	-50.69	IWA	49.86	20.00	-29.86	T4	
		5MHz	376000	0923M	3.47	-46.23			49.70	20.00	-29.70	T4	
		5MHz	370500	0923M	3.47	-46.48			49.95	20.00	-29.95	T4	

Table 6-3 Raw Data Results for NR TDD n41 (OTT VolP)

			170	w Data	Nesult	2 101 IA	וו טטו א	- 1 (O 1	. vo. ,				
Mode	Orientation	Bandwidth	Channel	Sample S/N	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		100MHz	518598	0468M	10.47	-25.07			35.54	20.00	-15.54	T4	
		90MHz	518598	0468M	10.47	-25.12			35.59	20.00	-15.59	T4	
		80MHz	518598	0468M	10.47	-24.84			35.31	20.00	-15.31	T4	
		60MHz	518598	0468M	10.47	-25.42			35.89	20.00	-15.89	T4	
		50MHz	518598	0468M	10.47	-25.42			35.89	20.00	-15.89	T4	
	Axial	40MHz	534000	0468M	10.47	-24.13	-58.13	N/A	34.60	20.00	-14.60	T4	0.8, 2.4
		40MHz	526302	0468M	10.47	-27.81			38.28	20.00	-18.28	T4	
		40MHz	518598	0468M	10.47	-24.76			35.23	20.00	-15.23	T4	
		40MHz	510900	0468M	10.47	-23.19			33.66	20.00	-13.66	T4	
		40MHz	503202	0468M	10.47	-22.76			33.23	20.00	-13.23	T4	
NR n41		20MHz	518598	0468M	10.47	-25.05			35.52	20.00	-15.52	T4	
NK 1141		100MHz	518598	0468M	3.47	-37.86			41.33	20.00	-21.33	T4	
		90MHz	518598	0468M	3.47	-37.68			41.15	20.00	-21.15	T4	
		80MHz	529998	0468M	3.47	-37.00	1		40.47	20.00	-20.47	T4	
		80MHz	524298	0468M	3.47	-38.47	1		41.94	20.00	-21.94	T4	
		80MHz	518598	0468M	3.47	-37.45	1		40.92	20.00	-20.92	T4	
	Radial	80MHz	512898	0468M	3.47	-36.69	-58.89	N/A	40.16	20.00	-20.16	T4	0.8, 1.6
		80MHz	507204	0468M	3.47	-38.04	1		41.51	20.00	-21.51	T4	
		60MHz	518598	0468M	3.47	-38.19			41.66	20.00	-21.66	T4	1
		50MHz	518598	0468M	3.47	-38.09			41.56	20.00	-21.56	T4	1
		40MHz	518598	0468M	3.47	-37.76			41.23	20.00	-21.23	T4	1
		20MHz	518598	0468M	3.47	-37.81			41.28	20.00	-21.28	T4	

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II. Test Notes

A. General

- 1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
- 2. 'Radial' orientation refers to radial transverse.
- 3. Bluetooth and WIFI were disabled while testing 5G modes.
- 4. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T4).

B. OTT VoIP

- 1. Vocoder Configuration: 75kbps
- 2. NR FDD Configuration
 - a. Power Configuration: TxAGC is set such that the DUT operates at max power.
 - b. Radio Configuration: DFT-s-OFDM, π/2-BPSK, 1RB, 50% RB Offset
 - c. NR n2 was the worst-case band from Table 5-2 and was used to test both Axial and Radial probe orientations.
 - d. Due to equipment limitations, ABM1 measurements were not possible. Therefore, additional ABM1 measurements with LTE OTT VoIP were used from the Original Certification Test Report and combined with NR ABM2 measurements to obtain SNNR values. Additionally, Frequency Response measurements were not possible due to equipment limitations.
 - e. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. NR FDD n2 at 20MHz is the worst-case for the Axial probe orientation. NR FDD n2 at 5MHz bandwidth is the worst-case for the Radial probe orientation.
- 3. NR TDD Configuration
 - a. Power Configuration: TxAGC is set such that the DUT operates at max power.
 - b. Radio Configuration: DFT-s-OFDM, π/2-BPSK, 1RB, 50% RB Offset
 - c. Due to equipment limitations, ABM1 measurements were not possible. Therefore, additional ABM1 measurements with LTE OTT VoIP were used from the Original Certification Test Report and combined with NR ABM2 measurements to obtain SNNR values. Additionally, Frequency Response measurements were not possible due to equipment limitations.
 - d. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. NR TDD n41 at 40MHz is the worst-case for the Axial probe orientation. NR TDD n41 at 80MHz bandwidth is the worst-case for the Radial probe orientation.

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III. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -20 dBm0 for OTT VoIP. This measurement was taken in the axial configuration above the maximum location.

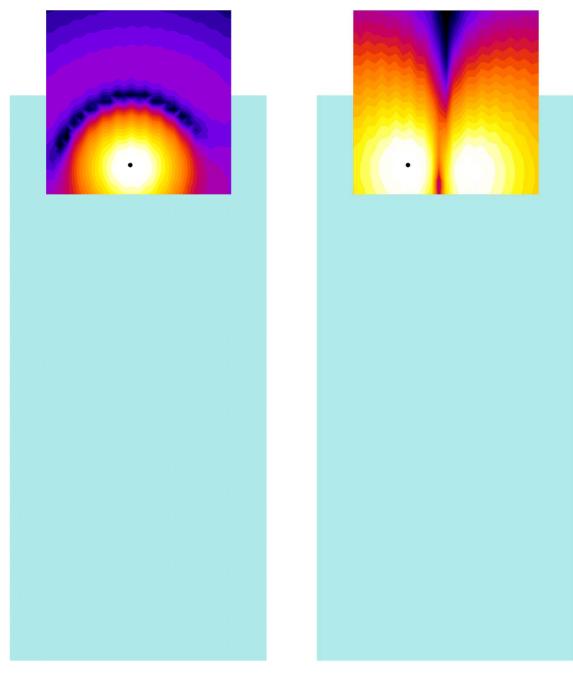
IV. T-Coil Validation Test Results

Table 6-4
Helmholtz Coil Validation Table of Results

Item	Target	Result	Verdict
Axial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-9.952	PASS
Environmental Noise	< -58 dBA/m	-58.13	PASS
Frequency Response, from limits	> 0 dB	0.80	PASS
Radial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.059	PASS
Environmental Noise	< -58 dBA/m	-58.89	PASS
Frequency Response, from limits	> 0 dB	0.80	PASS

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ABM1 Magnetic Field Distribution Scan Overlays ٧.



Axial Radial (Transverse)

Figure 6-1 T-Coil Scan Overlay Magnetic Field Distributions

Notes:

- 1. Final measurement locations are indicated by a cursor on the contour plots.
- 2. See Test Setup Photographs for actual WD overlay.

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MEASUREMENT UNCERTAINTY

Table 7-1 **Uncertainty Estimation Table**

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)			
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%				
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%				
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%				
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%				
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%				
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%				
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%				
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%				
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%				
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%				
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%				
Combined standard uncertainty, uc (k=1) 17.7%										
Expanded uncertainty (k=2),	95% conf	Expanded uncertainty (k=2), 95% confidence level								

Notes:

- 1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
- All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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8. EQUIPMENT LIST

Table 8-1 Equipment List

	=4					
Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Control Company	4040	Therm./Clock/Humidity Monitor	6/29/2019	Biennial	6/29/2021	192291463
Dell	Latitude E6540	SoundCheck Acoustic Analyzer Laptop	9/6/2018	Biennial	9/6/2020	2655082910
Listen	SoundConnect	Microphone Power Supply	9/6/2018	Biennial	9/6/2020	0899-PS150
RME	Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	9/6/2018	Biennial	9/6/2020	23792992
Seekonk	NC-100	Torque Wrench (8" lb)	5/10/2018	Biennial	5/10/2020	21053
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A
TEM	Axial T-Coil Probe	Axial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1123
TEM	Radial T-Coil Probe	Radial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1129
TEM	Helmholtz Coil	Helmholtz Coil	10/10/2018	Biennial	10/10/2020	SBI 1052

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9. TEST DATA

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DUT: HH Coil - SN: SBI 1052

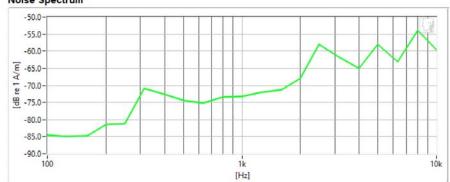
Type: HH Coil Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

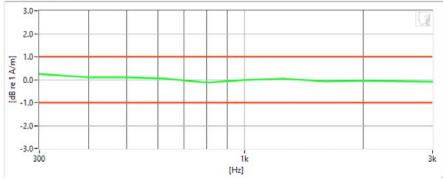
Equipment:

- Probe: Axial T-Coil Probe SN: TEM-1123; Calibrated: 09/19/2018
- Helmholtz Coil SN: SBI 1052; Calibrated: 10/10/2018

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-9.952 dB	~	Max/Min	-9.5/-10.5
Verification ABM2	-58.13 dB	•	Maximum	-58.0
Frequency Response Margin	800m dB	✓	Tolerance curves	Aligned Data

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PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil - SN: SBI 1052

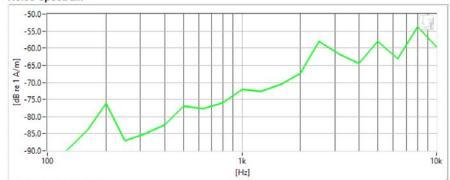
Type: HH Coil Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

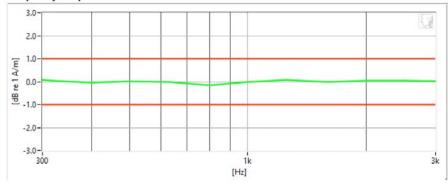
Equipment:

- Probe: Radial T-Coil Probe SN: TEM-1129; Calibrated: 09/19/2018
- Helmholtz Coil SN: SBI 1052; Calibrated: 10/10/2018

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-10.059	dB	•	Max/Min	-9.5/-10.5
Verification ABM2	-58.89	dB	•	Maximum	-58.0
Frequency Response Margin	800m	dB	~	Tolerance curves	Aligned Data

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Type: Portable Handset Serial: 0468M

Measurement Standard: ANSI C63.19-2011

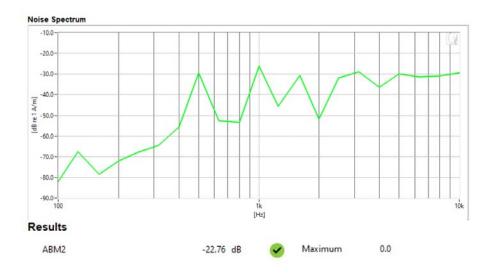
Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 09/19/2018

Test Configuration:

VolP Application: Google Duo

Mode: NR TDD n41 Bandwidth: 40MHz Channel: 503202



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DUT: A3LSMG986U

Type: Portable Handset Serial: 0468M

Measurement Standard: ANSI C63.19-2011

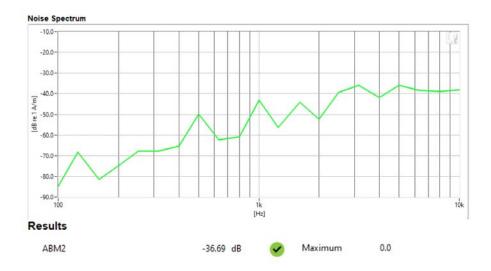
Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 09/19/2018

Test Configuration:

VolP Application: Google Duo
 Mode: NR TDD n41

Bandwidth: 80MHz
Channel: 512898



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10. CALIBRATION CERTIFICATES

FCC ID: A3LSMG986U	PCTEST houd to be part of & seneral	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 30 of 42
1M2003120043-21-R1.A3L	3/16/2020 - 3/19/2020	Portable Handset		Faye 30 01 42

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Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by:

TEM CONSULTING LP

Model No:

AXIAL T COIL PROBE

Serial No: Calibration Recall No: TEM-1123 29156

Submitted By:

Customer:

Andrew Harwell

Company:

PCTest Engineering Lab

Address:

6660-B Dobbin Road

Columbia

MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No.

AXIAL T C TEM C

Upon receipt for Calibration, the instrument was found to be:

12/4/2019

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.
The information supplied relates to the calibrated item listed above.
West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Approved by: Fc

Calibration Date:

19-Sep-18

Felix Christopher (QA Mgr.)

Certificate No:

29156 -2

West Caldwell

ISO/IEC 17025:2005

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

ACCREDITED

uncompromised calibration Laboratories, Inc.

1575 State Route 96, Victor, NY 14564, U.S.A.

Calibration Lab. Cert. # 1533.01

 FCC ID: A3LSMG986U
 PCTEST
 HAC (T-COIL) TEST REPORT
 Approved by: Quality Manager

 Filename:
 Test Dates:
 DUT Type:

 1M2003120043-21-R1.A3L
 3/16/2020 - 3/19/2020
 Portable Handset

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1575 State Route 96, Victor NY 14564



REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe Company: PCTest Enginering Lab

Model No.: Axial T Coil Probe

Serial No.: TEM-1123 I. D. No.: XXXX

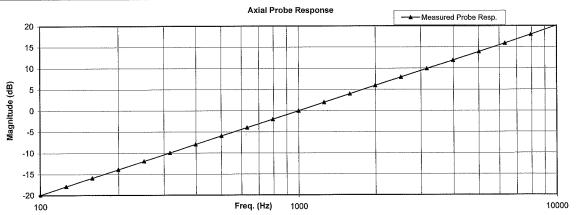
Calibration results: Probe Sensitivity measured with Helmholtz Coil Helmholtz Coll; Before & after data same: ... X ... the number of turns on each coil; 10 No. 0.204 Laboratory Environment: the radius of each coil, in meters; Ambient Temperature: °C 0.08 22.7 Α the current in the coils, in amperes.; 7.09 A/m/V Ambient Humidity: % RH Helmholtz Coil Constant; Helmholtz Coil magnetic field; 5.95 A/m Ambient Pressure: 99.326 Calibration Date: 19-Sep-2018 Calibration Due: Probe Sensitivity at 1000 Hт -59.89 dBV/A/m. Report Number: 29156 -2 was 1.013 mV/A/m Control Number: 29156 903 Ohms Probe resistance The above listed instrument meets or exceeds the tested manufacturer's specifications.

683/284413-14

This Calibration is traceable through NIST test numbers:

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure : Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, IŞØ)17025

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

Measurements performed by:

James Zhu

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

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FCC ID: A3LSMG986U	PCTEST hoad to be part of ® sement	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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HCATEMC_TEM-1123_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Axial T Coil Probe Company: PCTest Enginering Lab

for Model No.: Axial T Coil Probe

Serial No.: TEM-1123

Function	Tolerance		Measured values		
			Before	Out	Remarks
Probe Sensitivity at	1000 Hz.	dBV/A/m	-59.89		
		dB			
Probe Level Linearity		6	6.03		
	Ref. (0 dB)	0	0.00		
		-6	-6.03		
		-12	-12.05		
	W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W W 1 W 1 W W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1 W 1	Hz			
Probe Frequency Response		100	-19.9		
		126	-17.9		
		158	-15.9		
		200	-13.9		
		251	-11.9		
		316	-9.9		
		398	-7.9		
		501	-6.0		
		631			
		794	-2.0		
	Ref. (0 dB)	1000	0.0		
		1259	2.0		
		1585	4.0		
		1995	5.9		
		2512	7.9		
		3162	9.9		
		3981	11.9		
		5012	13.9		
•		6310	15.9		
		7943	18.0		
		10000	20.1		
	Probe Sensitivity at Probe Level Linearity	Probe Sensitivity at 1000 Hz. Probe Level Linearity Ref. (0 dB)	Probe Sensitivity at 1000 Hz. dBV/A/m Probe Level Linearity Ref. (0 dB) Ref. (0 dB) O -6 -12 Probe Frequency Response Hz Probe Frequency Response 100 126 158 200 251 316 398 501 631 794 Ref. (0 dB) 1000 1259 1585 1995 2512 3162 3981 5012 6310 7943	Probe Sensitivity at 1000 Hz. dBV/A/m -59.89 Probe Level Linearity 6 6 6.03 Ref. (0 dB) 0 0.00 -6 -6.03 -12 -12.05 Probe Frequency Response 100 -19.9 158 -15.9 200 -13.9 251 -11.9 316 -9.9 398 -7.9 501 -6.0 631 -4.0 794 -2.0 Ref. (0 dB) 1000 0.0 1259 2.0 1585 4.0 1995 5.9 2512 7.9 3162 9.9 3981 11.9 5012 13.9 6310 15.9 7943 18.0	Probe Sensitivity at 1000 Hz. dBV/A/m -59.89 Probe Level Linearity 6

Instruments used for ca	alibration:		Date of Cal.	Traceablity No.	Due Date
HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	,287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

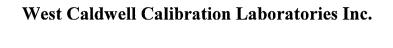
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Tested by: James Zhu

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FCC ID: A3LSMG986U	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 33 of 42
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Certificate of Calibration

for

RADIAL T COIL PROBE

Manufactured by:

TEM CONSULTING LP

Model No:

RADIAL T COIL PROBE

Serial No: Calibration Recall No: TEM-1129 29156

Submitted By:

Customer:

Andrew Harwell

Company: Address:

PCTest Engineering Lab 6660-B Dobbin Road

Columbia

MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No.

RADIAL T TEM C

Upon receipt for Calibration, the instrument was found to be:

10/4/2015

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.
The information supplied relates to the calibrated item listed above.
West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Approved by: FC

Calibration Date:

19-Sep-18

Felix Christopher (QA Mgr.)

Certificate No:

29156 -1

ISO/IEC 17025:2005

QA Doc. #1051 Rev. 2.0 10/1/01 Certificate Page 1 of 1

Calibration

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uncompromised calibration Laboratories, Inc.

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Calibration Lab. Cert. # 1533.01

 FCC ID: A3LSMG986U
 PCTEST
 HAC (T-COIL) TEST REPORT
 Approved by: Quality Manager

 Filename:
 Test Dates:
 DUT Type:

 1M2003120043-21-R1.A3L
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 Portable Handset

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HCRTEMC_TEM-1129_Sep-19-2018



1575 State Route 96, Victor NY 14564



REPORT OF CALIBRATION

for

TEM Consulting LP Radial T Coil Probe ,Company: PCTest Engineering Lab Model No.: Radial T Coil Probe

Serial No.: TEM-1129

I. D. No.: XXXX

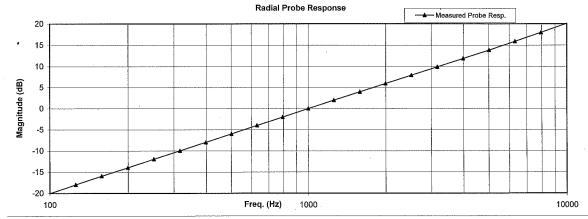
Probe Sensitivity measured wit	h Helmhol	tz Coil			
Helmholtz Coil;			Before & after data same:	X	
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.08	Α	Ambient Temperature:	22.7	°C
Helmholtz Coil Constant;	7.09	A/m/V	Ambient Humidity:	52.1	% RH
Helmholtz Coil magnetic field;	5.95	A/m	Ambient Pressure:	99.326	kPa
			Calibration Date:	19-Sep-2018	
Probe Sensitivity at	1000	Hz.	Re-calibration Due:		
was	-60.37	dBV/A/m	Report Number:	29156	-1
	0.958	mV/A/m	Control Number:	29156	
Probe resistance	886	Ohms		•	

This Calibration is traceable through NIST test numbers:

683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISQ 17025

Cal. Date: 19-Sep-2018

Measurements performed by: James Zhu

Calibrated on WCCL system type 9700

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Filename:	Test Dates:	DUT Type:		Page 35 of 42
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HCRTEMC_TEM-1129_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe Company: PCTest Engineering Lab

for Model No.: Radial T Coil Probe

Serial No.: TEM-1129

	Function Tolerance		Measured values		
rido como como como como como como como co	——————————————————————————————————————		Before	Out	Remarks
Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.37		
		dB			
Probe Level Linearity		6	6.03		
	Ref. (0 dB)	0	0.00		
		-6	-6.03		
		-12	-12.05		
		Hz			
Probe Frequency Response			1		
			1		
	Ref. (0 dB)				
			1 1		
			18.0		
		10000	20.1		
		Probe Level Linearity Ref. (0 dB)	Probe Level Linearity Ref. (0 dB) Ref. (0 dB) -6 -12 Probe Frequency Response 100 126 158 200 251 316 398 501 631 794	Probe Level Linearity Ref. (0 dB) Ref. (0 dB)	Probe Level Linearity Ref. (0 dB) Ref. (0 dB)

Instruments used for o	alibration:		Date of Cal.	Traceability No.	Due Date
' HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	,287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

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Tested by: James Zhu

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

Page 2 of 2

FCC ID: A3LSMG986U	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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11. CONCLUSION

The measurements taken in accordance with the procedures provided in the CTIA Test Plan for Hearing Aid Compatibility Rev 3.1.1, May 2017, indicate that NR modes of the wireless communications device complies with the HAC limits specified in the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

FCC ID: A3LSMG986U	PCTEST . Road to be part of § removed	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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1M2003120043-21-R1.A3L	3/16/2020 - 3/19/2020	Portable Handset		Page 37 of 42

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FCC ID: A3LSMG986U	PCTEST:	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 39 of 42
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